

In the Claims:

1. (Currently Amended) A test circuit for a semiconductor integrated circuit device for being put to a delay test using a scan path test circuit incorporated therein for a scan path test, comprising:

a two-pulse generator for generating two pulses spaced from each other by a pulse interval equal to a period of a test clock for the delay test which is input from an external source, from said test clock, and supplying the generated two pulses to the scan path test circuit[.];

wherein said two-pulse generator comprises a gate signal generator for generating a gate signal to extract two pulses from said test clock and a latch gate circuit for outputting two pulses from said test clock according to said gate signal.

2. (Currently Amended) A test circuit semiconductor integrated circuit device according to claim 1, wherein said test circuit is fabricated in said semiconductor integrated circuit device and further comprises comprising:

a PLL circuit for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said two-pulse generator.

3. (Currently Amended) A test circuit according to claim 1, wherein said test circuit is mounted on a test board, and said semiconductor integrated circuit device is removably mounted on said test board. A semiconductor integrated circuit device according to claim 1, wherein said two-pulse generator comprises:

a gate signal generator for generating a gate signal to extract two pulses from said test clock; and

a latch gate circuit for outputting two pulses from said test clock according to said gate signal.

4. (Currently Amended) A test circuit according to claim 3, further comprising:

a PLL circuit for multiplying the frequency of said test clock and supplying a signal having the multiplied-frequency to said two-pulse generator.

~~A semiconductor integrated circuit device according to claim 2, wherein said two-pulse generator comprises:~~

~~a gate signal generator for generating a gate signal to extract two pulses from said test clock; and~~

~~a latch gate circuit for outputting two pulses from said test clock according to said gate signal.~~

5. (Withdrawn) A device for testing a semiconductor integrated circuit device for being put to a delay test using a scan path test circuit incorporated in the semiconductor integrated circuit device for a scan path test, comprising:

a test board on which a semiconductor integrated circuit device to be tested is removably mounted; and

a two-pulse generator mounted on said test board, for generating two pulses spaced from each other by a pulse interval equal to a period of a test clock for the delay test, from said test clock, and supplying the generated two pulses to the scan path test circuit.

6. (Withdrawn) A device according to claim 5, further comprising:

a PLL circuit mounted on said test board, for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said two-pulse generator.

7. (Withdrawn) A device according to claim 5, further comprising:

a clock generator for outputting said test clock.

8. (Withdrawn) A device according to claim 6, further comprising:

a clock generator for outputting said test clock.

9. (Withdrawn) A device according to claim 5, said two-pulse generator comprises:
- a gate signal generator for generating a gate signal to extract two pulses from said test clock; and
 - a latch gate circuit for outputting two pulses from said test clock according to said gate signal.
10. (Withdrawn) A device according to claim 6, said two-pulse generator comprises:
- a gate signal generator for generating a gate signal to extract two pulses from said test clock; and
 - a latch gate circuit for outputting two pulses from said test clock according to said gate signal.
11. (Withdrawn) A device according to claim 7, said two-pulse generator comprises:
- a gate signal generator for generating a gate signal to extract two pulses from said test clock; and
 - a latch gate circuit for outputting two pulses from said test clock according to said gate signal.
12. (Withdrawn) A device according to claim 8, said two-pulse generator comprises:
- a gate signal generator for generating a gate signal to extract two pulses from said test clock; and
 - a latch gate circuit for outputting two pulses from said test clock according to said gate signal.
13. (Withdrawn) A device according to 5, further comprising:
- a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

14. (Withdrawn) A device according to 6, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
15. (Withdrawn) A device according to 7, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
16. (Withdrawn) A device according to 8, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
17. (Withdrawn) A device according to 9, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
18. (Withdrawn) A device according to 10, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
19. (Withdrawn) A device according to 11, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
20. (Withdrawn) A device according to 12, further comprising:
a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.
21. (Currently Amended) A test circuit according to claim 3, further comprising:

~~a clock generator for outputting said test clock. A device for testing a semiconductor integrated circuit device, comprising:~~

~~a test board on which a semiconductor integrated circuit device according to claim 1 is removably mounted; and~~

~~a clock generator mounted on said test board, for outputting said test clock.~~

22. (Currently Amended) A test circuit according to claim 3, further comprising:

a frequency divider mounted on said test board, for dividing the frequency of said test clock into a frequency which can easily be measured.

~~A device for testing a semiconductor integrated circuit device, comprising:
a test board on which a semiconductor integrated circuit device according to claim 2 is removably mounted; and~~

~~a clock generator mounted on said test board, for outputting said test clock.~~

23. (Currently Amended) A test circuit according to claim 1, further comprising:

a clock generator for outputting said test clock,
wherein said two-pulse generator is fabricated in said semiconductor integrated circuit device, and said semiconductor integrated circuit device is removably mounted to a test board, and said clock generator is mounted on said test board.

~~A device for testing a semiconductor integrated circuit device, comprising:
a test board on which a semiconductor integrated circuit device according to claim 3 is removably mounted; and~~

~~a clock generator mounted on said test board, for outputting said test clock.~~

24. (Currently Amended) ~~A device for testing a semiconductor integrated circuit device, comprising:~~

~~a test board on which a semiconductor integrated circuit device according to claim 4 is removably mounted; and~~

~~a clock generator mounted on said test board, for outputting said test clock.~~

A test circuit according to claim 23, further comprising:
a PLL circuit for multiplying the frequency of said test clock and supplying a
signal having the multiplied-frequency to said two-pulse generator,
wherein said PLL circuit is fabricated in said semiconductor integrated circuit device.

25. (Withdrawn) A device according to claim 21, further comprising:

a second PLL circuit mounted on said test board, for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said semiconductor integrated circuit device.

26. (Withdrawn) A device according to claim 22, further comprising:

a second PLL circuit mounted on said test board, for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said semiconductor integrated circuit device.

27. (Withdrawn) A device according to claim 23, further comprising:

a second PLL circuit mounted on said test board, for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said semiconductor integrated circuit device.

28. (Withdrawn) A device according to claim 24, further comprising:

a second PLL circuit mounted on said test board, for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said semiconductor integrated circuit device.

29. (Withdrawn) A device according to claim 21, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

30. (Currently Amended) ~~A device according to claim 22, further comprising:~~

~~a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured~~ A test circuit according to claim 23, further comprising:

a second PLL circuit mounted on said test board, for multiplying a frequency of said test clock and supplying a signal having the multiplied-frequency to said semiconductor integrated circuit device.

31. (Withdrawn) A device according to claim 23, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

32. (Currently amended) A test circuit device according to claim ~~[[24]]~~ 23, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

33. (Withdrawn) A device according to claim 25, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

34. (Withdrawn) A device according to claim 26, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

35. (Withdrawn) A device according to claim 27, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.

36. (Withdrawn) A device according to claim 28, further comprising:

a frequency divider mounted on said test board, for dividing a frequency of said test clock into a frequency which can easily be measured.